



**BSI Standards Publication**

## **Semiconductor devices — Micro-electromechanical devices**

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Part 40: Test methods of micro-electromechanical inertial shock switch threshold

## National foreword

This British Standard is the UK implementation of IEC 62047-40:2021.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its committee manager.

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Published by BSI Standards Limited 2021

ISBN 978 0 539 07033 0

ICS 31.080.99

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This British Standard was published under the authority of the Standards Policy and Strategy Committee on 30 September 2021.

### Amendments/corrigenda issued since publication

| Date | Text affected |
|------|---------------|
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